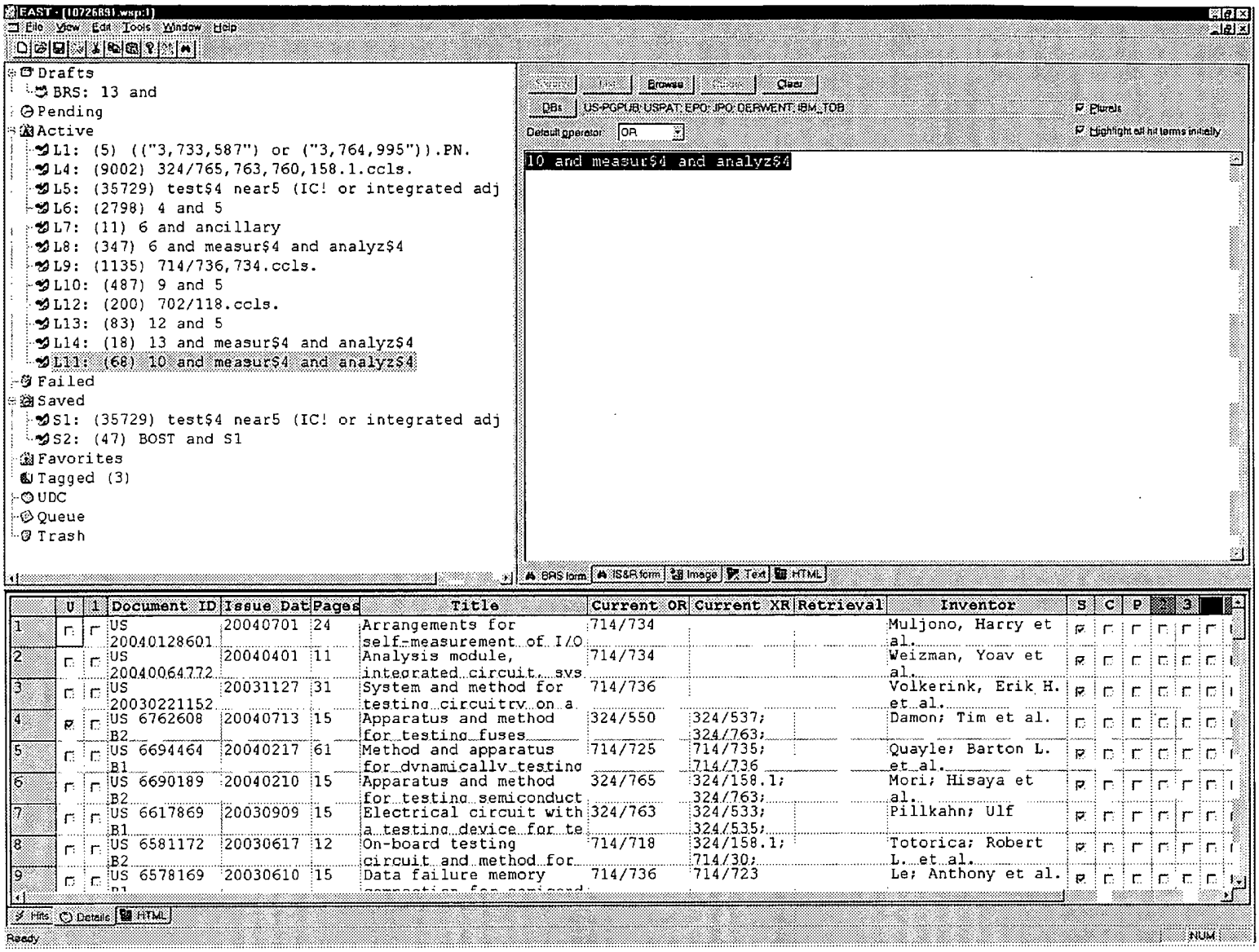
EAST - [10726831.wsp:1]
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Drafts
BRS: 13 and
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L1: (5) (("3,733,587") or ("3,764,995")).PN.
L4: (9002) 324/765,763,760,158.1.ccls.
L5: (35729) test$4 near5 (IC! or integrated adj
L6: (2798) 4 and 5
L7: (11) 6 and ancillary
L8: (347) 6 and measur$4 and analyz$4
L9: (1135) 714/736,734.ccls.
L10: (487) 9 and 5
L12: (200) 702/118.ccls.
L13: (83) 12 and 5
L14: (18) 13 and measur$4 and analyz$4
L11: (68) 10 and measur$4 and analyz$4
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S1: (35729) test$4 near5 (IC! or integrated adj
S2: (47) BOST and S1
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10 and measur$4 and analyz$4
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Title
Current OR
Current XR
Retrieval
Inventor
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1 US 20040128601 20040701 24 Arrangements for self-measurement of I/O 714/734 Muljono, Harry et al.
2 US 20040064772 20040401 11 Analysis module, integrated circuit, sys 714/734 Weizman, Yoav et al.
3 US 20030221152 20031127 31 System and method for testing circuitry on a 714/736 Volkerink, Erik H. et al.
4 US 6762608 B2 20040713 15 Apparatus and method for testing fuses 324/550 324/537; 324/763; Damon; Tim et al.
5 US 6694464 B1 20040217 61 Method and apparatus for dynamically testing 714/725 714/735; 714/736 Quayle; Barton L. et al.
6 US 6690189 B2 20040210 15 Apparatus and method for testing semiconduct 324/765 324/158.1; 324/763; Mori; Hisaya et al.
7 US 6617869 B1 20030909 15 Electrical circuit with a testing device for te 324/763 324/533; 324/535; Pillkahn; Ulf
8 US 6581172 B2 20030617 12 On-board testing circuit and method for 714/718 324/158.1; 714/30; Totorica; Robert L. et al.
9 US 6578169 B1 20030610 15 Data failure memory 714/736 714/723 Le; Anthony et al.
Hits
Details
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